

INTERNATIONAL SEARCH REPORT

Inte	Application No
PCT/IB2005/050509	

A. CLASSIFICATION OF SUBJECT MATTER		
IPC 7	G06F1/00	H04L9/06

According to International Patent Classification (IPC) or to both national classification and IPC		
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B. FIELDS SEARCHED		
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Minimum documentation searched (classification system followed by classification symbols)		
IPC 7	G06F	H04L

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched		
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Electronic data base consulted during the international search (name of data base and, where practical, search terms used)		
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EPO-Internal		
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C. DOCUMENTS CONSIDERED TO BE RELEVANT		
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Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 2003/132777 A1 (LAACKMANN PETER ET AL) 17 July 2003 (2003-07-17) the whole document -----	1-10
X	US 2003/218475 A1 (GAMMEL BERNDT) 27 November 2003 (2003-11-27) the whole document -----	1-10
X	US 5 861 652 A (COLE ET AL) 19 January 1999 (1999-01-19) the whole document -----	1-10 -/-

<input checked="" type="checkbox"/>	Further documents are listed in the continuation of box C.
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<input checked="" type="checkbox"/>	Patent family members are listed in annex.
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* Special categories of cited documents :

- *A* document defining the general state of the art which is not considered to be of particular relevance
- *E* earlier document but published on or after the international filing date
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- *O* document referring to an oral disclosure, use, exhibition or other means
- *P* document published prior to the international filing date but later than the priority date claimed

- *T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
- *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
- *Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.
- *&* document member of the same patent family

Date of the actual completion of the international search	Date of mailing of the international search report
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17 May 2005	25/05/2005
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Name and mailing address of the ISA	Authorized officer
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European Patent Office, P.B. 5818 Patentlaan 2 NL - 2280 HV Rijswijk Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Fax (+31-70) 340-3016	Mäenpää, J
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PCT/IB2005/050509

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	CHEN J C ET AL: "An on-chip,-interconnect capacitance characterization method with sub-femto-farad resolution" IEEE TRANSACTIONS ON SEMICONDUCTOR MANUFACTURING, IEEE INC, NEW YORK, US, vol. 11, no. 2, 1 May 1998 (1998-05-01), pages 204-210, XP002096116 ISSN: 0894-6507 the whole document -----	1-10
A	LAQUAI B ET AL: "A new method and test structure for easy determination of femto-farad on-chip capacitances in a MOS process" PROCEEDINGS OF THE INTERNATIONAL CONFERENCE ON MICROELECTRONIC TEST STRUCTURES (ICMTS). SAN DIEGO, MAR. 16 - 19, 1992, NEW YORK, IEEE, US, 16 March 1992 (1992-03-16), pages 62-66, XP010059392 ISBN: 0-7803-0535-3 the whole document -----	1-10
A	KHALKHAL A ET AL: "ON-CHIP MEASUREMENT OF INTERCONNECT CAPACITANCES IN A CMOS PROCESS" PROCEEDINGS OF THE INTERNATIONAL CONFERENCE ON MICROELECTRONIC TEST STRUCTURES (ICMTS). NARA, JP., MAR. 22 - 25, 1995, NEW YORK, IEEE, US, 22 March 1995 (1995-03-22), pages 145-149, XP000547658 ISBN: 0-7803-2066-2 the whole document -----	1-10
A	ANDERSON R ET AL: "TAMPER RESISTANCE - A CAUTIONARY NOTE" PROCEEDINGS OF THE USENIX WORKSHOP OF ELECTRONIC COMMERCE, November 1996 (1996-11), pages 1-11, XP000923039 the whole document -----	1-10
A	LASH T: "A STUDY OF POWER ANALYSIS AND THE ADVANCED ENCRYPTION STANDARD" MS SCHOLARLY PAPER GEORGE MASON UNIVERSITY, February 2002 (2002-02), pages A-B,1, XP001130987 the whole document -----	1-10

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 Inte Application No
 PCT/IB2005/050509

Patent document cited in search report	Publication date		Patent family member(s)		Publication date
US 2003132777	A1	17-07-2003	EP WO JP TW	1182702 A1 0217398 A1 2004507112 T 507307 B	27-02-2002 28-02-2002 04-03-2004 21-10-2002
US 2003218475	A1	27-11-2003	DE BR CN WO EP JP MX TW	10044837 C1 0113810 A 1460203 A 0221241 A2 1334416 A2 2004508630 T PA03002064 A 539935 B	13-09-2001 13-01-2004 03-12-2003 14-03-2002 13-08-2003 18-03-2004 06-10-2003 01-07-2003
US 5861652	A	19-01-1999	AU DE DE EP WO	2301997 A 69706043 D1 69706043 T2 0892988 A1 9736326 A1	17-10-1997 13-09-2001 06-12-2001 27-01-1999 02-10-1997